



**DEFENSE LOGISTICS AGENCY**  
DLA LAND AND MARITIME  
POST OFFICE BOX 3990  
COLUMBUS, OH 43218-3990

Sept 26, 2017

Mr. Daniel Rossiter  
Oneida Research Services, Inc.  
8282 Halsey Road  
Whitesboro, NY 13492

Dear Mr. Rossiter:

Re: VQE-17-031763 Commercial Laboratory Suitability Status, MIL-STD-750, FSC 5961, MIL-STD-883, FSC 5962, Control Number 058266

As a result of our data review, your facility at the above address is considered suitably equipped to perform testing on military devices for the following test methods of MIL-STD-883:

<u>TEST</u>	<u>METHOD</u>	<u>CONDITION</u>
Seal	1014	A1, A2, A5, B1, B2, B1/B2 and B3
External Visual	2009	N/A
Internal Visual (Monolithic)	2010	A, B
Radiography	2012	Non-Film (Digital) and Film
Physical Dimensions	2016	N/A
Internal Visual (Hybrid)	2017	H and K
SEM	2018	N/A
PIND	2020	A, B
Internal Gas Analysis	1018	N/A
Bond Strength	2011	Condition D
Die Shear	2019	N/A
Internal Visual (Passive)	2032	H and K

In addition, your facility is considered suitably equipped to perform testing on military devices for the following test methods of MIL-STD-750:

<u>TEST</u>	<u>METHOD</u>	<u>CONDITION</u>
Internal Gas Analysis	1018	N/A
Seal	1071	A, B, G1, G2, H1, H2, H3
Die Attach Integrity	2017	Condition A
Bond Strength (Destructive Bond Pull)	2037	Condition D
Physical dimensions	2066	
PRE-CAP visual, power MOSFET'S	2069	
Visual and mechanical examination	2071	
Internal Visual transistor (PRE-CAP) inspection	2072	
Visual inspection for die (semiconductor diode)	2073	
Decap Internal Visual Design Verification	2075	
Radiography	2076	Non-Film (Digital) and Film
SEM	2077	N/A
PIND	2052	A, B
Destructive Physical Analysis for wire bonded devices	2102	

This suitability for test method 1018 for both MIL-STD-883 and MIL-STD-750 is limited to the internal gas analysis machines with serial numbers EQ-01-015 and EQ-06-009. This suitability is limited to internal volumes greater than or equal to 0.01 cm<sup>3</sup> for EQ-01-015 and to internal volumes greater than or equal to 0.0006 cm<sup>3</sup> for EQ-06-009 for MIL-STD-883 and for MIL-STD-750 tests.

The suitability for test method 1071, Condition H3 and test method 1014, Condition A5 is limited to internal volumes greater than 0.01 cm<sup>3</sup> as demonstrated.

This suitability is valid until terminated by written notification from the office of primary interest (OPI), qualifying activity. Your laboratory may be re-audited on a drop-in basis and commercial laboratory suitability may be withdrawn by this Center at any time.

This suitability prohibits your company from removing or altering the device marking. Any device that fails testing conditions shall be identified (isolated) as a reject and returned to the device manufacturer for verification of failure mode or the device(s) shall be destroyed with manufacturer approval under government witness.

The approved test methods and procedures shall be used for all military testing. Any time the test method is specified in a contract or purchase order, etc., you must comply fully with the specified test method. Whenever the military standard is specified, the testing must be performed in accordance with the DLA Land and Maritime approved procedure, to all the military standard requirements, and in accordance with what was demonstrated during the DLA Land and Maritime audit. Any exceptions to the DLA Land and Maritime approved test method must be clearly stated in the contract. However, under no circumstances can changes, exceptions, waivers, etc., be applied when a test is done on a QPL or QML product unless the test method is officially amended or revised by the preparing activity of the military document.

Electrostatic discharge sensitivity (ESDS) requirements are enforced by this Center. Therefore, all hybrid/monolithic and discrete semiconductor electronic devices will be handled as ESD sensitive to the applicable category of the devices under test, unless otherwise notified by the device manufacturer. Consequently, all processing procedures will incorporate the handling, testing, and packaging requirements according to the guidelines in MIL-HDBK-263 and JESD625.

To maintain laboratory suitability status for the above listed test methods, you are required to compile a summary of all hybrid/monolithic and discrete semiconductor electronic devices tested to the requirements of the above test methods. This summary and other information described below shall be submitted every twelve months.

Your standard reporting period will include work performed from February 1 through January 31. Your next retention report shall be submitted to DLA Land and Maritime by March 1, 2018. The retention report shall include the items in section IV of DLA Land and Maritime's Laboratory Suitability Information booklet.

The use of your laboratory for performing testing is subject to conditions stated in 4120.24-M and SD-6.

If you have any questions, please contact Mr. Alan Barone at (614) 692-0510.

Sincerely,

RAYMOND L. KOLONCHUK  
Chief  
Electronic Devices Branch